Notice of References Cited Application/Control No. 10/609,477 Examiner TAN X. DINH Applicant(s)/Patent Under Reexamination ENDO ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,388,959 B1	05-2002	Kondo, Tadaharu	369/30.19
*	В	US-6,137,642 A	10-2000	Inoue, Hiraku	369/53.24
*	С	US-5,862,104 A	01-1999	Matsumoto, Kissei	369/7
*	D	US-5,751,678 A	05-1998	Tanaka, Yozo	369/53.24
*	E	US-5,732,059	03-1998	Katsuyama et al.	369/47.12
*	F	US-6,556,518 B2	04-2003	Isobe et al.	369/30.19
*	G	US-5,963,521 A	10-1999	Nagashima et al.	369/53.37
*	Н	US-6,493,299 B2	12-2002	Sato, Katsuyuki	369/47.12
*	1	US-6,388,965 B2	05-2002	Ozawa et al.	369/47.12
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	ρ					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	>	
	8	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.